

## 10A, 40V N-CHANNEL MOSFET

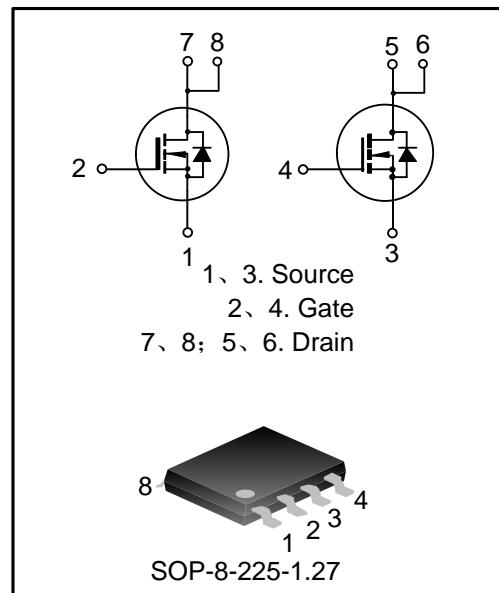
### DESCRIPTION

SVT1040SA is an N-channel enhancement mode power MOS field effect transistor which is produced using Trench Mos technology. The improved trench stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are widely used in UPS, DC-DC converters.

### FEATURES

- ◆ 10A, 40V,  $R_{DS(on)(typ.)}=15m\Omega @ V_{GS}=10V$
- ◆ Low gate charge
- ◆ Low Crss
- ◆ Fast switching
- ◆ Improved dv/dt capability



### ORDERING INFORMATION

Part No.	Package	Marking	Hazardous substance control	Packing
SVT1040SA	SOP-8-225-1.27	SVT1040	Halogen free	Tube
SVT1040SATR	SOP-8-225-1.27	SVT1040	Halogen free	Tape & reel



**ABSOLUTE MAXIMUM RATINGS (PER DEVICE, UNLESS OTHERWISE NOTED,  $T_J=25^\circ\text{C}$ )**

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		$V_{DS}$	40	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Drain Current	$T_C=25^\circ\text{C}$	$I_D$	10	A
	$T_C=100^\circ\text{C}$		6.3	
Drain Current Pulsed		$I_{DM}$	40	A
Power Dissipation ( $T_C=25^\circ\text{C}$ ) -Derate above $25^\circ\text{C}$		$P_D$	3.2	W
			0.03	$\text{W}/^\circ\text{C}$
Single Pulsed Avalanche Energy	(Note 1)	$E_{AS}$	98	mJ
Operation Junction Temperature Range		$T_J$	-55~+150	$^\circ\text{C}$
Storage Temperature Range		$T_{stg}$	-55~+150	$^\circ\text{C}$

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	39	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	85	$^\circ\text{C}/\text{W}$

## ELECTRICAL CHARACTERISTICS (PER DEVICE, UNLESS OTHERWISE NOTED, $T_c=25^\circ\text{C}$ )

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	$B_{VDSS}$	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	40	--	--	V
Drain-Source Leakage Current	$I_{bss}$	$V_{DS}=40\text{V}, V_{GS}=0\text{V}$	--	--	1.0	$\mu\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	--	--	$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{GS}=V_{DS}, I_D=250\mu\text{A}$	1.0	--	2.0	V
Static Drain- Source On State Resistance	$R_{DS(\text{on})}$	$V_{GS}=10\text{V}, I_D=10\text{A}$	--	9.0	13	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=10\text{A}$		11	16	$\text{m}\Omega$
Input Capacitance	$C_{iss}$	$f=1\text{MHz}, V_{GS}=0\text{V}, V_{DS}=25\text{V}$	--	1870	--	pF
Output Capacitance	$C_{oss}$		--	156	--	
Reverse Transfer Capacitance	$C_{rss}$		--	136	--	
Turn-on Delay Time	$t_{d(\text{on})}$	$V_{DD}=20\text{V}, V_{GS}=10\text{V}, R_G=3.3\Omega, I_D=10\text{A}$ (Note 2,3)	--	8.2	--	ns
Turn-on Rise Time	$t_r$		--	52	--	
Turn-off Delay Time	$t_{d(\text{off})}$		--	55	--	
Turn-off Fall Time	$t_f$		--	19	--	
Total Gate Charge	$Q_g$	$V_{DD}=20\text{V}, I_D=10\text{A}, V_{GS}=10\text{V}$ (Note 2,3)	--	38	--	nC
Gate-Source Charge	$Q_{gs}$		--	7.4	--	
Gate-Drain Charge	$Q_{gd}$		--	6.7	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS(PER DEVICE)

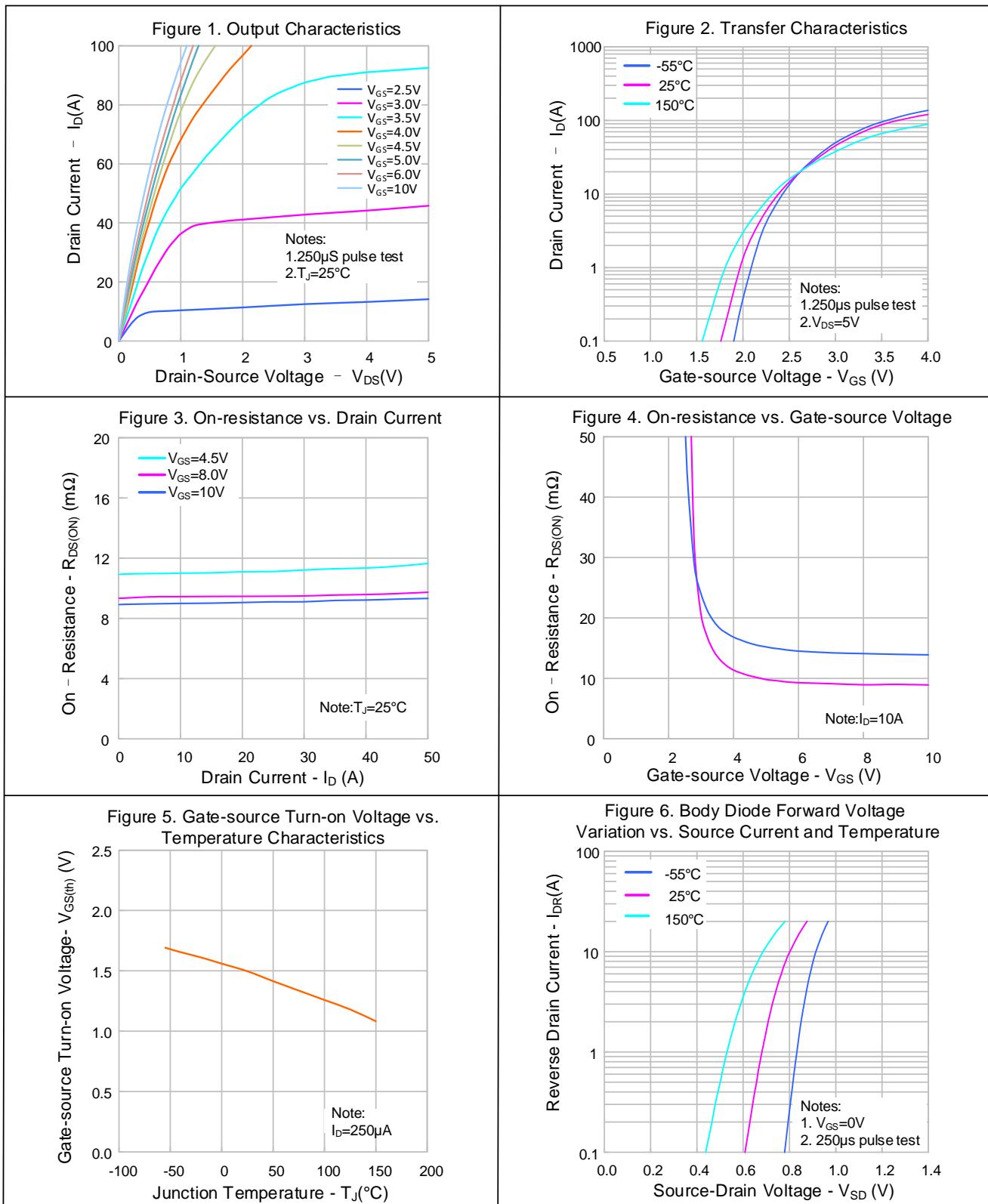
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_s$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	10	A
Pulsed Source Current	$I_{SM}$		--	--	40	
Diode Forward Voltage	$V_{SD}$	$I_s=10\text{A}, V_{GS}=0\text{V}$	--	--	1.4	V
Reverse Recovery Time	$T_{rr}$	$I_s=10\text{A}, V_{GS}=0\text{V}, V_R=40\text{V}, dI/dt=100\text{A}/\mu\text{s}$	--	14	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	7.7	--	nC

### Notes:

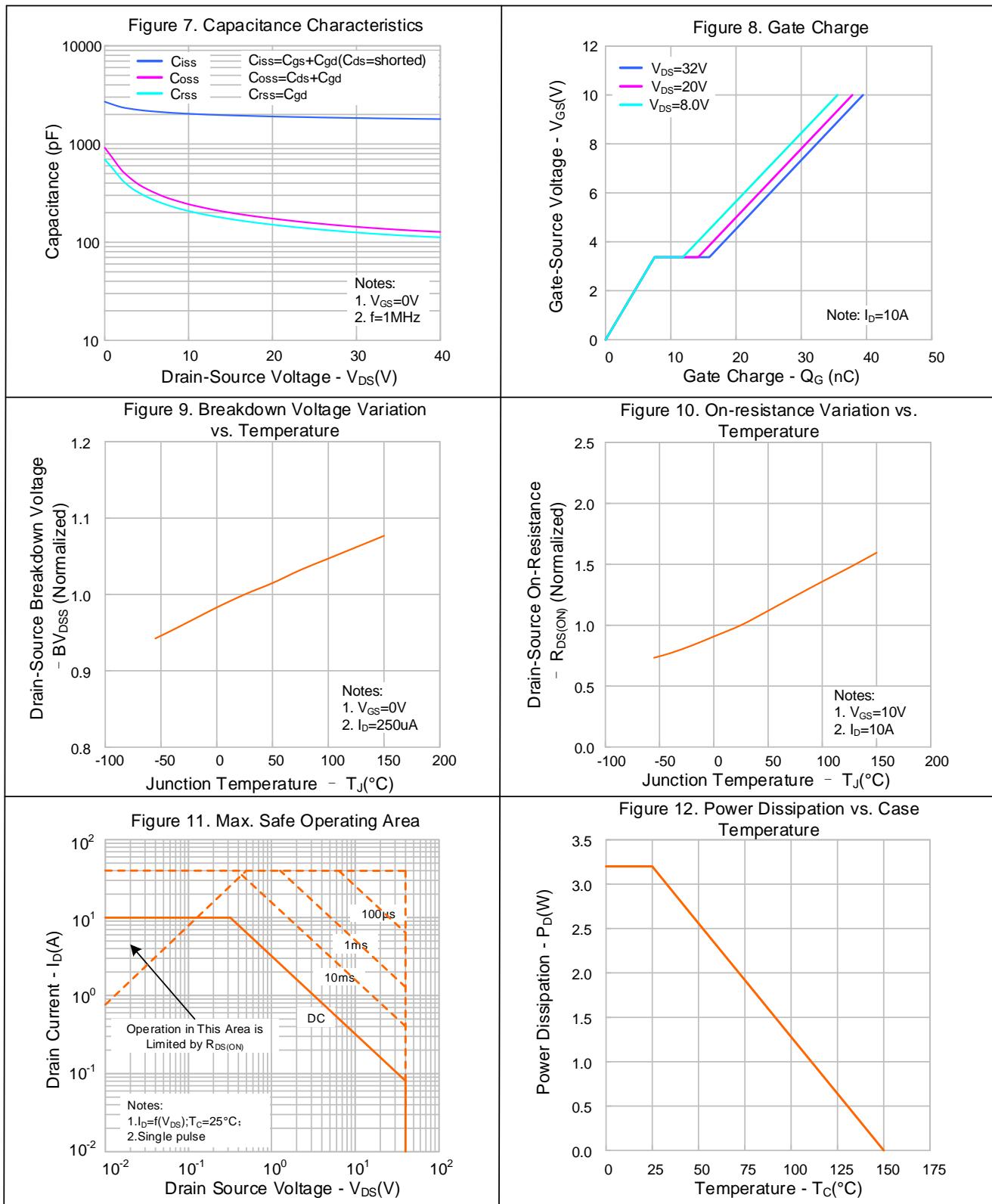
1.  $L=1\text{mH}, I_{AS}=14\text{A}, V_{DD}=25\text{V}, R_G=20\Omega$ , starting  $T_j=25^\circ\text{C}$ ;
2. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$ ;
3. Essentially independent of operating temperature.



TYPICAL CHARACTERISTICS (PER DEVICE)

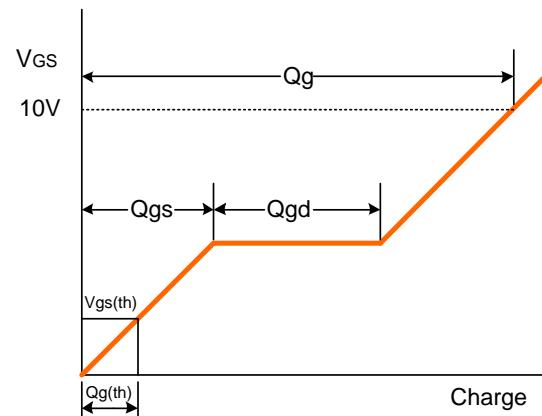
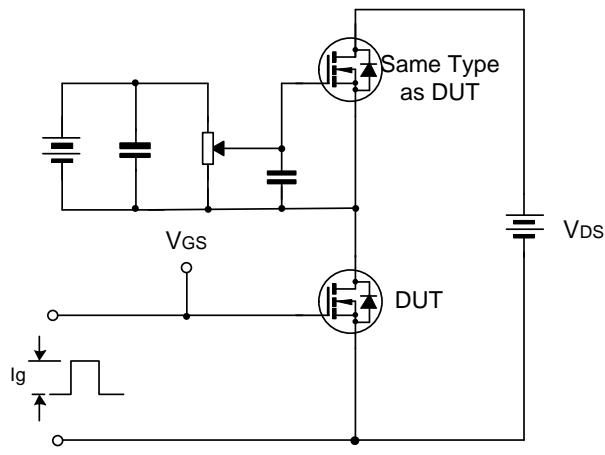


## TYPICAL CHARACTERISTICS (CONTINUED)

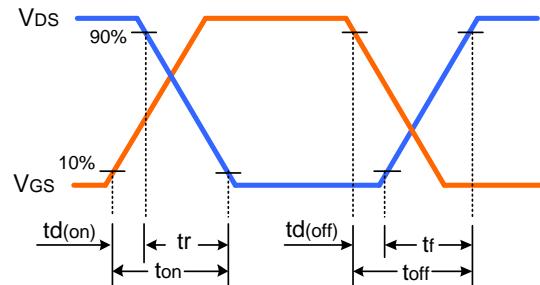
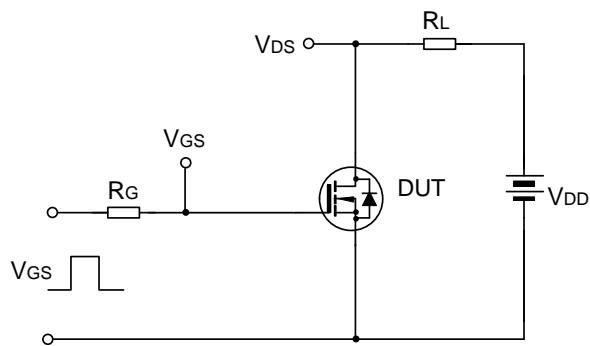


## TYPICAL TEST CIRCUIT

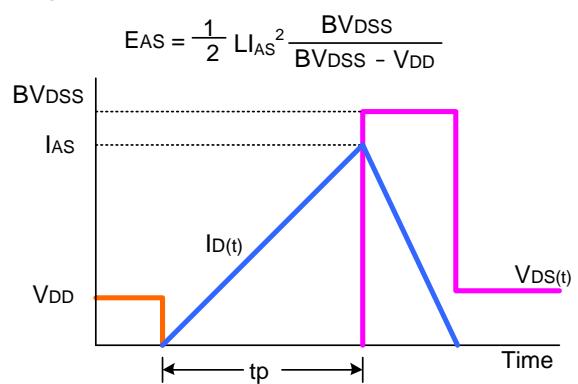
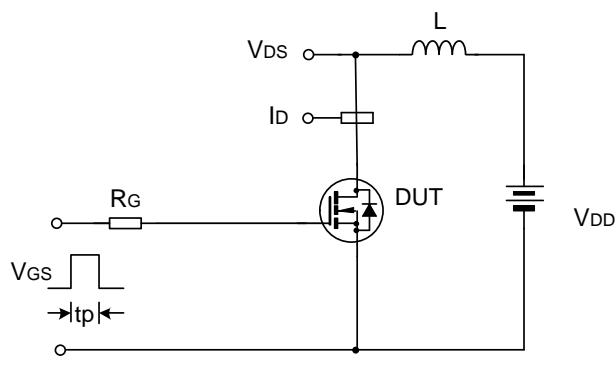
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



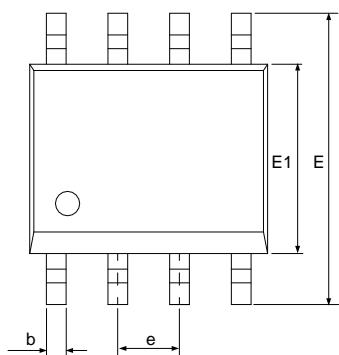
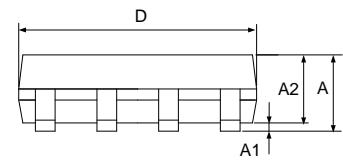
Unclamped Inductive Switching Test Circuit & Waveform



## PACKAGE OUTLINE

SOP-8-225-1.27

UNIT: mm



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	1.35	1.55	1.75
A1	0.05	0.15	0.25
A2	1.25	—	1.65
b	0.32	0.42	0.52
c	0.15	0.20	0.26
D	4.70	4.90	5.30
E	5.60	6.00	6.40
E1	3.60	3.90	4.20
e	1.27BSC		
L	0.30	—	1.27

### Important notice :

1. The instructions are subject to change without notice!
2. Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current. Please read the instructions carefully before using our products, including the circuit operation precautions.
3. Our products are consumer electronic products or the other civil electronic products.
4. When using our products, please do not exceed the maximum rating of the products, otherwise the reliability of the whole machine will be affected. There is a certain possibility of failure or malfunction of any semiconductor product under specific conditions. The buyer is responsible for complying with safety standards and taking safety measures when using our products for system design, sample and whole machine manufacturing, so as to avoid potential failure risk that may cause personal injury or property loss.
5. It is strongly recommended to identify the trademark when buying our products. Please contact us if there is any question.
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Rev.: **1.2**

Revision History:

1. Update the curve
  2. Update electrical characteristics
  3. Update electrical diagram and typical test circuit
  4. Update package outline
  5. Update important notice
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Rev.: **1.1**

Revision History:

1. Modify the Circuit symbol
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Rev.: **1.0**

Revision History:

1. First release
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